

MESO

Interferometry Applications

Metrology solution
Simpler, faster & more robust

Insensitive to vibrations
At-wavelength metrology
Parallel optics testing



**imagine
optic**

MESO DATASHEET 2411

MESO +

New metrology solution for easy at-wavelength testing of flat surfaces in any environment

MESO is the perfect tool for
the characterization of:

- + Parallel Optics
- + Screens
- + Filters, dichroics
- + Mirrors
- + Beamsplitters
- + Windows, substrates
- + Corner cubes
- + Crystals
- + Rods, disks
- + Glass wafers
- + Displays
- + Machined surfaces
- + Windshields
- + Prisms
- + Large lenses
- + Optical systems, beam expanders

APPLICATIONS

- + In situ process control
- + Thin Parallel Optics characterization
- + Transmitted wavefront quality (TWE)
- + Surface shape & flatness measurement (RWE)
- + Large optics testing
- + Wedge measurement

FEATURES

- + Insensitive to vibrations thanks to fast single shot acquisition and the lack of need for a reference arm for comparison. It allows for a standalone setup compatible with shop floor metrology!
- + At-wavelength sample testing due to its achromatic system embedding up to 4 light sources, automatically controlled by the User Interface.
- + Insensitive to reflections from the back surface of the sample thanks to a unique patent pending method. No surface preparation of the sample is needed, avoiding added steps that could disturb the metrology and put the sample at risk.
- + Smart maintenance: On-site user install or replacement of sources with no opening of optical areas and no realignment needed.



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SPECIFICATIONS*

OPERATING SPECS

Phase point resolution
Minimum exposure time
Calibrated range
Working output wavelengths
Output polarization
Operating system & software

VIS VERSION

680 x 500
27 ms
405 nm to 830 nm
405, 488, 520, 635, 785, 830 nm custom
optional linear, circular
Windows 10 & 11,
WAVESURF™ acquisition control & analysis software

SWIR VERSION

160 x 128
27 ms
1050 nm to 1700 nm
1050, 1300, 1550 nm custom
optional linear, circular
Windows 10 & 11,
WAVESURF™ acquisition control & analysis software

OPTICAL SPECS

Optical configuration
Test beam diameters

double-pass
optical zoom
from 1.5" (38.1 mm) up to 6" (152 mm)
4.25" (108 mm)

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optical zoom
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MISC

Dimensions (Height x Width x Length)
Weight
Mounting configuration
Camera
Interface
Warranty
Vibration isolation
Compressed air
Sample reflectivity
Sample min. thickness
RMS wavefront repeatability**
Accessories

29.6 x 31 x 78.9 cm³
27 kg
horizontal or vertical
4096 x 3000 pixels, 10 bits
USB 3.0
1 year system & laser standard, extendable
not necessary
not necessary
1% - 100 %, no attenuation required
100 μm
1 nm
High performance Dell™ computer
24" touchscreen

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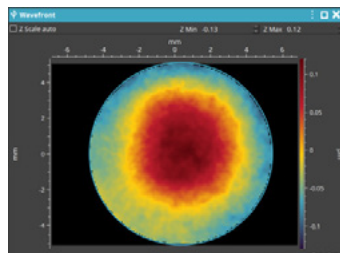
** From a set of 36 measurements on a Ø4" diameter flat mirror, each of them averaged 16 times, a synthetic reference is defined by the mean of the 18 odd measurements.
The RMS wavefront repeatability is then defined by the mean RMS difference plus 2x the standard deviation of the difference between the 18 even measurements and the synthetic reference.

*Subject to changes without further notice

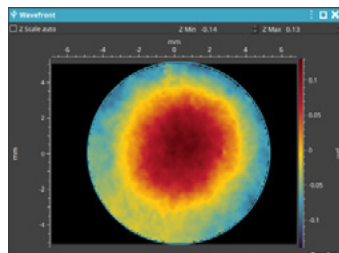


ACHROMATISM

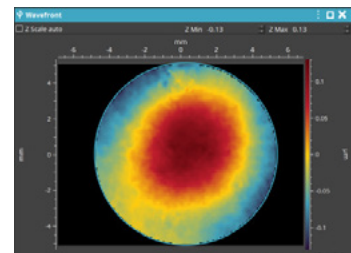
Plane optics measured on Ø4" diameter at 3 wavelengths: wavefront error variation is less than 4 nm RMS (< 1/150)



wavelength: 402 nm
wfe: 53 nm RMS



wavelength: 635 nm
wfe: 57 nm RMS



wavelength: 785 nm
wfe: 57 nm RMS

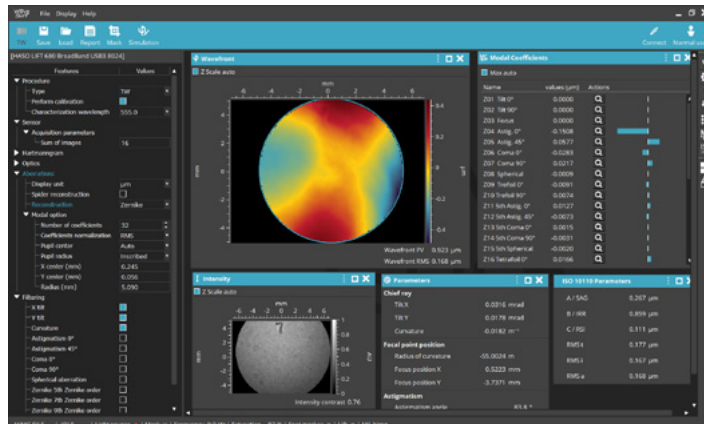
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SOFTWARE

WAVESURF™

Easy-to-use interface

WAVESURF™ allows operators and engineers in manufacturing environments to perform wavefront and surface characterization of flat optics and large lenses with just a few clicks. Scripted testing procedures guide users through all the steps. It makes control easy, automated and error-proof.



- + Touchscreen interface control
- + Scripted testing procedures guide the user through all the steps
- + Automated control of up to 4 embedded wavelengths
- + Automated control of test diameter (optical zoom)
- + Complete automated test report
- + ISO10110 standard compliance
- + Data format compatible with CODE V® and MetroPro™

WHITE PAPERS

- + Shop floor measurement: vibration-proofed solutions for optical metrology
- + At-wavelength metrology for optical systems and surfaces
- + Parallel optics testing: simultaneous characterization of both optical faces in laboratory and manufacturing conditions



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